

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-207001	Application No. <i>10/756 756</i> New Application
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hajime Kimura et al.	
		Filing Date January 14, 2004	Group Art Unit <i>2673</i>

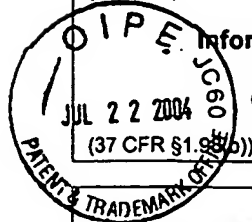
U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
<i>JP</i>	AL	2003-066909	03/05/2003	JAPAN	—	—	ABS	
<i>JP</i>	AM	2003-150112	05/23/2003	JAPAN	—	—	ABS	
<i>JP</i>	AN	2003-195812	07/09/2003	JAPAN	—	—	ABS	
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>JP</i>	AQ	Reiji Hattori et al.; "Circuit Simulation of Poly-Si TFT Based Current-writing Active-Matrix Organic LED Display"; <i>Technical Report of IEICE, ED2001-8, SDM2001-8</i> ; The Institute of Electronics, Information and Communication Engineers, pp. 7-14; 2001
	AR	
	AS	
	AT	

Examiner Signature <i>Jeff Piziali</i>	Date Considered <i>6-20-2005</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-207001	Application No. 10/756,756
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hajime Kimura et al.	
		Filing Date January 14, 2004	Group Art Unit 2673



## U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
JP	AA	2001/0048410 A1	12/06/2001	Nishigaki et al.	345	82	08/07/2001
JP	AB	2002/0135313 A1	09/26/2002	Koyama	315	169.3	03/21/2002
JP	AC	5,973,661	10/26/1999	Kobayashi et al.	345	100	12/20/1995
JP	AD	6,222,357 B1	04/24/2001	Sakuragi	323	315	09/03/1999
JP	AE	6,310,589 B1	10/30/2001	Nishigaki et al.	345	76	05/27/1998
JP	AF	6,545,651 B2	04/08/2003	Nishigaki et al.	345	76	08/07/2001
JP	AG	6,693,385 B2	02/17/2004	Koyama	315	169.1	03/21/2002

## Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
JP	AH	02-189579	07/25/1990	JAPAN	—	—	ABS	
JP	AI	05-042488	10/26/1993	JAPAN	—	—	FULL	
JP	AJ	09-081087	03/28/1997	JAPAN	—	—	ABS	
JP	AK	09-134149	05/20/1997	JAPAN	—	—	ABS	
JP	AL	09-244590	09/19/1997	JAPAN	—	—	ABS	
JP	AM	11-045071	02/16/1999	JAPAN	—	—	ABS	
JP	AN	2000-081920	03/21/2000	JAPAN	—	—	ABS	
JP	AO	2002-351404	12/06/2002	JAPAN	—	—	ABS	
JP	AP	2004-004789	01/08/2004	JAPAN	—	—	ABS	
JP	AQ	EP 0 718 816 A2	06/26/1996	EUROPE	—	—	IN ENGLISH	
JP	AR	WO 03/038793 A1	05/08/2003	PCT/WIPO	—	—	ABS	

## Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
JP	AS	International Search Report (Application No. PCT/JP03/16354) dated March 9, 2004
JP	AT	International Preliminary Examination Report (Application No. PCT/JP03/16354) dated April 20, 2004 with partial translation

Examiner Signature <i>Jeff Piziali</i>	Date Considered <i>6-20-05</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	